

Construction of an Electron Yield Detector for XAFS in SORIS at BL-8

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Abstract

An electron yield detector for X-ray Absorption Fine Structure (XAFS) was designed and installed in the SORIS (=Synchrotron Radiation and Ion Scattering) system at BL-8. Operating characteristics of the detector and a control system of the monochromator were tested by measuring C K-edge spectra of a graphite sample. Characteristic profiles and the polarization dependence of those spectra were confirmed.